

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1267	Apr-97	9705 A1	HYUNDAI	DL639421AAD	1.2μ OX/NI	16 SOIC

**STRESS/JOB NO.**

**READPOINT**

**(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-19484

<u>Electrical</u>	<u>Cum %</u>
235/0	0.0%

Sonoscan  
P-19515

<u>Post Vapor Phase</u>
4/0

Infant / High Voltage Life 125°C, -4.0 & +6.0 V P-19516, P-19552	<u>48 Hr</u>	<u>336 Hr</u>	<u>1K Hr</u>	<u>*Failure Rate</u>
	231/0	77/0	77/1	181 Fits
			F1	

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-19553	<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
	39/0	39/0	0.0%

Biased Moisture 85°C/85% RH, 5.5 V. P-19554	<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
	77/0	77/0	0.0%

Autoclave 121°C/100% RH, 2 Atmos P-19555	<u>168 Hr</u>	<u>Cum %</u>
	38/0	0.0%

**Failure Mode**

F1: Leakage

**Failure Analysis**

In process